

High-density plasma sputtering device

Damage-less sputtering / Independent control of ion energy and flux / Useable in ferromagnetic target

Overview

With the increase of request for device miniaturization and thin crystal film quality improvement, the ion damage on substrate has become a major issue in sputtering. The magnetron sputtering method is widely used but since the plasma is formed directly between the target material and the substrate, “① it is difficult to avoid ion damage”. This issue is amplified when generating high-density plasma. In addition, since a single power supply is responsible for both the plasma generation and ion attraction, “② it is impossible to independently control the ion flux and energy flowing into the target material”. Moreover, since the plasma is confined by the magnetic leakage flux on the target surface, “③ it is difficult to use for ferromagnetic material target”.

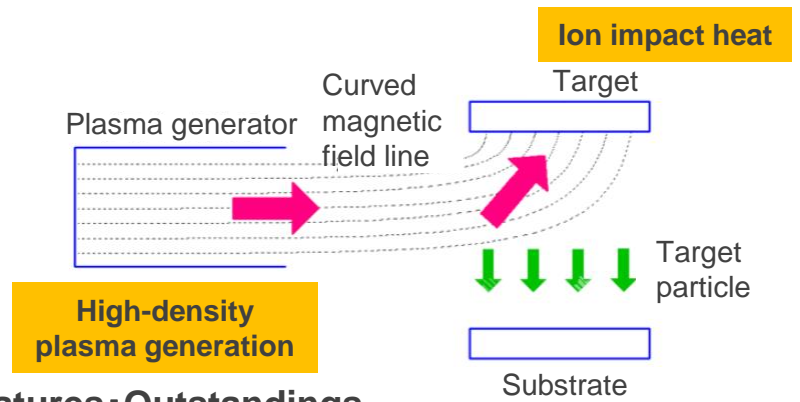
This invention solves above ①/②/③ issues by generating high-density plasma with helicon discharge and by controlling the plasma shape with a curved magnetic field, etc. This invention could also be considered to be used as a heating mechanism of the target material, or as an uniform & fast film deposition.

Product Application

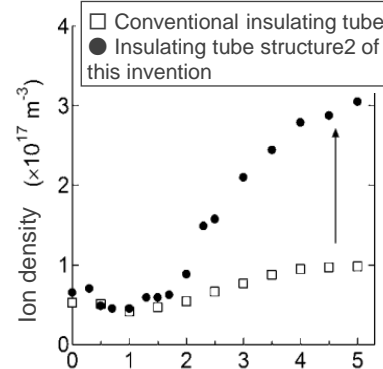
- ❑ High quality crystalline thin film formation without damage to substrate
- ❑ Film deposition from a thick ferromagnetic target material
- ❑ Film deposition of target material by repeated evaporation & sublimation
- ❑ Uniform film formation on large diameter target and substrate

IP Data

IP No. : WO2018-143164, US10854448
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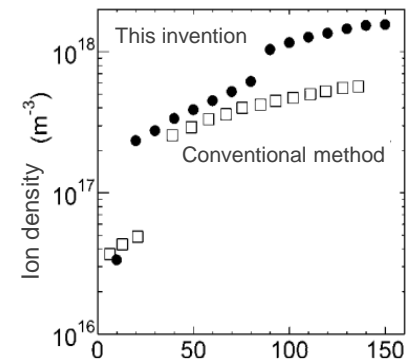


Features · Outstandings



Excitation current of the first electromagnet (A)

Plasma density increases with the “insulating tube structure” of this invention (●) compared to conventional method (□)



High frequency electric power (W)

Plasma density increases with the “curved magnetic field line” of this invention (●) compared to conventional method (□)

Related Works

- [1] T. Saito, K. Takahashi, et al., Vacuum, 163, 269 (2019).
- [2] K. Takahashi et al., Vacuum, 171, 109000 (2020).
- [3] TAKAHASHI Kazunori, Plasma Technologies in an Innovative Semiconductor Industrial System: Minimal Fab – Multi-Target Sputtering Tool Using a Helicon Plasma Source, J. Plasma Fusion Res. 10, 522 (2020).

Contact